

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/685,318	FANG ET AL.	
Examiner	Art Unit	
Matthew D. Matzek	1771	

	SEAR	CHED	
Class	Subclass	Date	Examiner
442	59 <sub>.</sub>	4/28/2005	MM M A
252	8.62	9/29/05	24,24
	-		

INT	ERFERENC	RFERENCE SEARCHED		
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	4/28/2005	MM		
UPPATED SEMICH	9/29/05	мМ		
Inventor Search	4/29/2005	MM		
ASSIGNEE	9/29/05	ма		
/ <b>6</b> S	9/24/05	MM		